Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under
10/598,181	Reexamination VATANEN ET AL	
Examiner	Art Unit	
NATHAN H. EMPIE	1792	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,937,093	06-1990	Chino et al.	427/10
*	В	US-5,837,324	11-1998	Yapel et al.	427/402
*	С	US-6,248,406	06-2001	Kondo et al.	427/420
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	T	US-			
	J	US-			
	к	US-			
	L	US-			·
	м	US-			

FOREIGN PATENT DOCUMENTS						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05104062 A	04-1993	Japan	ARAI, TAKAO	B05D 07/00
	0	JP 06142590 A	05-1994	Japan	NAKAMURA et al.	B05C 05/02
	Р	JP 2000343017 A	12-2000	Japan	OKADA et al.	B05C 05/02
	Q					
	R					
	s					
	Т					

NON DATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
-		include as applicable. Adulor, Tide Date, Publisher, Edition of Volume, Pertinent Pages)		
	U			
	v			
	w			
	x			

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.